High-performance Ultraviolet Photodetectors Based on ZnO Nanostructures

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Abstract—Zinc Oxide nanowires were prepared on an Indium Tin Oxide (ITO) substrate by a hydrothermal method which is renowned for its simple, low cost, and low temperature techniques. These wires prepared with different reaction times were demonstrated to be utilized as UV photodetectors. The morphology, elemental compositions, and crystallization of ZnO nanowire structures were analyzed by Field Emission Scanning Electron Microscopy (FE-SEM), X-Ray Spectroscopy (XPS), and X-Ray Diffraction (XRD), respectively. The optical properties of the nanodevices were measured by using UV-vis absorption spectrometer, and the properties of UV photodetectors were characterized by I-V curves. At a given bias voltage of 5 V, ZnO nanowire devices, prepared at the reaction time of 2 h, exhibited high photocurrent, high sensitivity, and fast response time to UV illumination as compared to the devices prepared at the reaction time of 5 h. A higher surface to volume ratio is the main contribution to those properties. These results suggest that the 2-hours ZnO nanowires exhibit great promise for the highly efficient UV photodetectors.

Index Terms—zinc oxide, nanowires, UV-photodetector

I. INTRODUCTION

ZnO is a semiconductor with wide direct band gap energy of 3.35 eV and a large exciton binding energy of 60 meV at room temperature [1]-[3]. It is widely used in optoelectronic devices and microelectronics due to their unique electrical and optical properties. Furthermore, ZnO is easy to prepare with various synthesis methods. ZnO also has lower growth temperature and material cost than other comparable materials. Recently, 1-D ZnO semiconducting nanostructures have been synthesized in various structures such as nanowires, nanorods, nanotubes, and nanobelts. These structures are attracting much attention as very promising candidates for many applications such as UV lasers, light emitting diodes, solar cells, nanogenerators, gas sensors, photodetectors, and photocatalysts [1]-[3]. Among these, ZnO nanowires (ZnO NWs) have attracted intensive research due to the large surface to volume ratio and high aspect ratio. These wires can possess a fast photo response upon illumination of UV light. Thus, it is widely used in ultraviolet (UV) photodectors [4]-[11]. In order to synthesize ZnO nanowires with controlled shape and ordered surface morphology, there has been reported by many different methods such as Vapor Liquid Solid (VLS) [12] and [13], Chemical Vapor Deposition (CVD) [14], Metal Organic Chemical Vapor Deposition (MOCVD) [15], Molecular Beam Epitaxy (MBE) [16], Pulsed Laser Deposition (PLD) [17], and so on. These methods mentioned above are carried out at higher temperatures, high vacuum, and expensive purification processes. Recently, solution phase including chemical bath deposition, (CBD) [18], solvothermal, hydrothermal, self-assembly [19], and sol-gel process have been employed to synthesize ZnO nanowires [20]-[22]. The solution phase method is the simplest, lowest cost, and lowest temperature method compared to those above. This paper focuses on lowcost and low temperature solution-based method for fabrication of UV photodetector with ZnO nanowires and nanorods on ITO substrates by aqueous solution. The advantages of aqueous solution are low cost, simple process, low temperature, and high product yield.

II. EXPERIMENTAL DETAILS

ZnO nanowire arrays were grown on indium thin oxide (ITO) substrate by solution-based technique. The ZnO nanowires were grown on a conductive ITO layer which deposited on a glass substrate with a sheet resistance of 10Ω/cm. The growth of ZnO nanowires were separated into 3 parts. First surface treatment, the cleaned ITO samples were irradiated with oxygen O3 plasma for 5 min in order to seed layer. Second the coating of seed particles, seed solution was prepared by dissolving 0.1-M zinc acetate [Zn(CH3COO)2·2H2O] and 10 ml of 2-methoxyethanol as a solvent, and the solution was mixed together in a beaker. This seed solution was spin-coated onto ITO substrate rotated at 2000 rpm for 30 s (3 cycles), and then it was heated at 150°C for 5 min to evaporate the solvent and remove the organic residuals. Finally, growth of ZnO nanowires, the ITO substrate that coated seed solution was put into a growth solution (0.1 M zinc nitrate hydrate, 0.1 M hexamethylenetetramine and 50 ml deionized (DI) water were mixed in beaker) and kept at a temperature of 90°C for 1-5h. After growth, the nanowire
ensembles were thoroughly rinsed with DI water and dried in an oven at a temperature of 90 °C overnight to reduce the residual contamination on the surface. The morphology and crystal nanostructure of ZnO were characterized by FE-SEM and XRD. Photo-response of ZnO devices were studied by applying a fixed bias voltage and measuring the change in current using a UV light source (Philips TL-D 18W) of power density 350 µWcm-2. Current-voltage (I-V) characteristics of the devices were measured both in the presence and absence of UV light by observing the change in current with the variation in bias voltage from -5 to +5 V.

III. RESULTS AND DISCUSSION

Figure 1. (a-d) the FE-SEM images and cross-section (inset) of ZnO nanowires for 1h, 2h, 3h and 5h, respectively, (e) graph of growth time on x-axis versus length of ZnO on Y-axis, and (f) XRD spectra of ZnO.

The morphology of as grown ZnO nanostructures on indium tin oxide coated glass substrates was examined by using FE-SEM. ZnO nanostructures were prepared with the growth time of 1, 2, 3, and 5h, and the results are shown in Fig. 1(a-d). The ZnO nanostructures had diameters in the range of ~10-30 nm and a length of ~1 µm, for the growth time of 1 h as shown in Fig. 1(a). At the growth time of 2h, the diameter and length were ~ 20-60nm and 1.2µm, respectively, as observed in Fig. 1(b). After the growth time of 5h, it was clearly observed that the morphology of ZnO nanowires was obtained with a diameter and length in the range of 50-120 nm and 1.4 µm, respectively, as shown in Fig. 1(d). The diameter of the nanowires increased with increasing the growth time. And the nanowires can transform to nanorod-like structures at the growth time of 5h. As the growth duration time increased, the diameter and height of ZnO nanowires increased gradually as shown in Fig. 1(e). This is because more Zn ions were diffused to the ZnO nuclei, thus forming ZnO nanorods [23]. XRD was performed to study the crystal structures of ZnO nanostructures. According to XRD pattern, shown in Fig. 1(f), the diffraction peaks of ZnO nanowires at 20 are 31.8°, 34.4°, 36.2°, 47.5°, 62.8°, respectively. All peaks are in good agreement with the standard spectrum (JCPDS nos. 36–1451 and 79–0205) for ZnO [20]-[22]. The high intensity of the (002) peak at 20 of 34.4° is corresponding to the hexagonal ZnO with wurtzite structure phase in ZnO nanowires. The nanowire structures were grown with highly c-axis oriented on the ITO glass substrate. Impurity peaks were not observed from XRD pattern, indicating that phase-pure and high quality ZnO nanostructures were obtained.

Figure 2. (a) UV-vis absorption, (b) XPS spectrum of the ZnO nanostructures, (c) high resolution of Zn2p, and (d) O1s.

The optical property of pure ZnO nanostructures was determined by UV-vis spectra as shown in Fig. 2(a). The UV absorption appeared from 360 to 400 nm for ZnO nanostructures, corresponding to the promotion of an electron from the valence band to the conduction band. The absorption edge of pure ZnO appears to be about 365 nm which corresponds to the band gap energy of ~3.35 eV at room temperature. The chemical states of the compositional elements in ZnO nanowire structures were characterized by the XPS. The survey XPS spectrum in the Fig. 2(b) shows that the Zn, C, and O peaks with the binding energy of each peak are calibrated by taking the C1s neutral carbon peak at the binding energy of 284.5 eV. XPS spectrum of Zn2p core-level shows double peaks at the binding energy of 1021 and 1044.28 eV corresponding to Zn 2p3/2 and Zn 2p1/2 electrons, respectively, and with spin-orbit splitting at about 23.28 eV as shown in Fig. 2(c). The high and sharp peak at the binding energy of 1021 eV indicates that the Zn 2p3/2 core level is associated with the Zn species in the completely oxidized state. The result of O 1s peak from XPS spectrum is important and interesting because it is not completely symmetrically as shown in Fig. 2(d). And the O1s peak was fitted with two Gaussian peaks. The dominant peak is located at the binding energy of 529.8
eV indicating that O2-ions in the ZnO are hexagonal wurtzite structure. Another peak is located at 531.3 eV corresponding to the adsorbed species containing the C–O bond. Typically, carbon atoms are being contaminated during the preparation process so that it may lead to the bonding of carbon and oxygen atoms.

Atomic ratio of Zn and O elements was estimated from the XPS results as shown in Fig. 3(a). The average atomic ratio of Zn/O was ~0.86. This result of Zn+2 excessive in the surface while the O2- deficiency may be presented as oxygen vacancy, Zn interstitials, or their complex [24] on the surface. It is able to capture and trap electrons and thus helps in effective photocatalytic degradation of organic pollutants under light irradiation. The I-V characteristic curves of ZnO nanodevices in dark and under UV illumination, (c) cyclical photoresponses of ZnO devices upon UV illumination with on and off light, (d) saturation current of ZnO nanostucture devices.

Figure 3. (a) atomic percent of Zn and O elements, (b) I-V characteristics of ZnO nanostucture devices in dark and under UV illumination, (c) cyclical photoresponses of ZnO devices upon UV illumination with on and off light, (d) saturation current of ZnO nanostucture devices.

The larger size of nanorods at 5h reduces the surface area which mainly results in a decrease of the photodetector under the same applied bias voltage. The sensitivity of the ZnO nanostructure devices was measured in the turn-on/off of UV illumination under the same conditions under the bias voltage of 5V. The dark current was about 1.5×10^-5 A flowing in the device, corresponding to a resistance of R~3.0×10^5 Ω at room temperature (I=Iuv+Idark). The depletion layer, formed at the surface of ZnO nanostucture, causes a low dark current because of less charge carrier concentrations. However, the photocurrent slightly increases after the ZnO nanostucture device was exposed to UV light (350 uW/cm-2). It can be seen that the photocurrent of ZnO nanostucture devices at different reaction time were ~2.2×10^-3 A (1h), ~3.5×10^-3 A (2h), ~1.2×10^-3 A (3h), and ~6.5×10^-3 A (5h), respectively. It is clearly observed that for all of ZnO nanostucture devices, the photocurrent under UV illumination is higher than dark current, indicating that the devices are highly UV sensitive to photoconductance. The photodetectors were also measured with UV light on and off for many cycles with different the reaction times as seen in Fig. 3(c). It indicates that the ZnO nanostucture devices can be reversibly switched between the low and the high conductivity states and shows an excellent stability in each cycle of 2 min. For the growth time of 5 h, it was observed that the current of the device rises rapidly from 0.01×10^-3 A to 0.05×10^-3 A within 10s and then slowly increases to 0.16×10^-3 A (for ZnO 5h). After turn-off the excitation, the photocurrent rapidly decreases within 10s and then slowly decreases to a minimum value. For ZnO nanostructure devices at growth time of 2h, the photocurrent rises instantly from 0.015×10^-3 A to 0.44×10^-3 A within 10s and then continually increases to 1.0×10^-3 A. The photocurrent decreases rapidly within 10s and then slightly decreases to minimum value after turning off the excitation as observed in Fig. 3(c). The results indicate that, the photoreponse of ZnO nanostructure devices at the growth time of 2h is higher than that of ZnO nanostucture devices with 5 h of growth time. According to the results, it can explain the effects of the size of the ZnO nanorods on the photocurrent. Under UV light at photon energies above semiconductor band gap, the electron (e-) and hole (+e) pairs are generated. The free electron holes are trapped by adsorbed O2 to be desorbed from the surface as defined by the following equation: $h^+ + O_2(ad) \rightarrow O_2(g)$. These chemisorption and photodesorption of oxygen molecules from the ZnO surface can result in an increase in the free carrier concentration and a decrease in the width of the depletion layer which lead to an enhancement of carrier injection transport and the higher photocurrent of the ZnO devices [22]. Due to a high surface to volume ratio of ZnO nanowires, it can further enhance the sensitivity of the devices which may lead to the realization of single photon detection. In addition, photoresponse depends on the ambient gas conditions such as it is slowed in vacuum and inert gases (up to several minutes) and fast in ambient air. Fig. 3(d) shows photocurrent saturation as a function of time of ZnO nanodevices at different the growth times of 1h to 5h under bias voltage of 5V. Photocurrent was measured by using UV light exposed to the devices until the photocurrent reaches its maximum value. The results show that photocurrent saturation are 1.4×10^-3 A, 8.5×10^-4 A, 6.6×10^-4 A, and 4.0×10^-4 A at reaction time of 2h, 1h, 3h, and 5h, respectively. In addition, the two key parameters, responsivity (Rs) and photocurrent gain (G), of photodetector are important.
The photocurrent saturation of devices was used to calculate the responsivity (Rs) and photocurrent gain (G). These properties were calculated by using the following equation:

\[ R_s = \frac{I_{ph}}{A_{area} \cdot P_{ir}} = \eta \cdot \frac{q \cdot A \cdot \lambda}{h} \cdot G \]  

(1)

The photoc conductive gain (G) of the detector is defined by the following equation:

\[ G = \frac{R_s \cdot \lambda}{q \cdot A} \]  

(2)

where \( I_{ph} = I_{light} - I_{dark} \) is the photocurrent (A), \( A_{area} \) is the effective device area (m2), \( P_{ir} \) is the incident light power (W/m2), \( \eta \) is the quantum efficiency, \( h \) is plank’s constant, \( c \) is the velocity of the light (m/s), and \( \lambda \) is the wavelength of incident light.

In this study, it was rationally chosen at the length of 2 \( \mu \)m which is the maximum penetration depth of the incident light in ZnO nanostructures. In addition, further increase in the rod length would increase its electrical resistance which is disadvantage to the enhancement of light capture.

IV. CONCLUSION

High quality ZnO nanowires were grown on ITO by using a simple, low cost, low temperature, hydrothermal method. Then UV photodetectors were fabricated out of ZnO nanowires with different reaction times. Measurements and analysis showed that the ZnO nano-devices exhibit a high photocurrent under the UV illumination of 365nm at a given bias voltage of 5V. Furthermore, responsivity and photoconductivity gain of ZnO nanostructure devices decreased when the reaction time was increased due to the surface to volume ratio being decreased with the increase in the reaction time. This study suggests the possibility of the promising applications in efficient UV photodetectors.

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